

METHOD FOR PRODUCING TEST PATTERNS FOR TESTING AN INTEGRATED CIRCUIT

ABSTRACT

5 A test pattern generation flow has a stimulus and a device under test
(DUT) that operate together through a test bench. The test bench monitors and
collects all the data necessary to generate a test program. This information is
presented as a captured simulation that allows for ease of generating test
software, as well as other simulations such as fault simulation and virtual test
10 simulation. The complete and convenient information can be utilized to
automate the development and/or easily manually develop and debug the test
software.